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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

## **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	6627
Number of Logic Elements/Cells	132540
Total RAM Bits	6747840
Number of I/O	1126
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1508-BBGA, FCBGA
Supplier Device Package	1508-FBGA, FC (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s130f1508c3n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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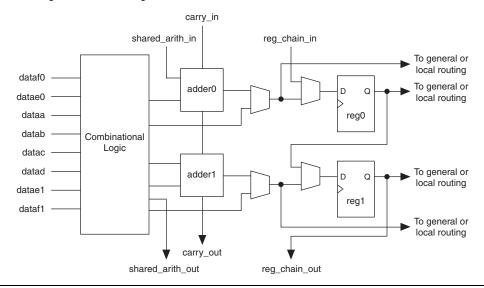
Visual Cue	Meaning
Italic type	Internal timing parameters and variables are shown in italic type. Examples: $t_{PlA}$ , $n+1$ .
	Variable names are enclosed in angle brackets (< >) and shown in italic type. Example: <file name="">, <project name="">.pof file.</project></file>
Initial Capital Letters	Keyboard keys and menu names are shown with initial capital letters. Examples: Delete key, the Options menu.
"Subheading Title"	References to sections within a document and titles of on-line help topics are shown in quotation marks. Example: "Typographic Conventions."
Courier type	Signal and port names are shown in lowercase Courier type. Examples: $\mathtt{datal}$ , $\mathtt{tdi}$ , $\mathtt{input}$ . Active-low signals are denoted by suffix $\mathtt{n}$ , $\mathtt{e.g.}$ , $\mathtt{resetn}$ .
	Anything that must be typed exactly as it appears is shown in Courier type. For example: c:\qdesigns\tutorial\chiptrip.gdf. Also, sections of an actual file, such as a Report File, references to parts of files (e.g., the AHDL keyword SUBDESIGN), as well as logic function names (e.g., TRI) are shown in Courier.
1., 2., 3., and a., b., c., etc.	Numbered steps are used in a list of items when the sequence of the items is important, such as the steps listed in a procedure.
•••	Bullets are used in a list of items when the sequence of the items is not important.
✓	The checkmark indicates a procedure that consists of one step only.
	The hand points to information that requires special attention.
CAUTION	The caution indicates required information that needs special consideration and understanding and should be read prior to starting or continuing with the procedure or process.
WARNING	The warning indicates information that should be read prior to starting or continuing the procedure or processes
4	The angled arrow indicates you should press the Enter key.
•••	The feet direct you to more information on a particular topic.

ii Altera Corporation

completely backward-compatible with four-input LUT architectures. One ALM can also implement any function of up to six inputs and certain seven-input functions.

In addition to the adaptive LUT-based resources, each ALM contains two programmable registers, two dedicated full adders, a carry chain, a shared arithmetic chain, and a register chain. Through these dedicated resources, the ALM can efficiently implement various arithmetic functions and shift registers. Each ALM drives all types of interconnects: local, row, column, carry chain, shared arithmetic chain, register chain, and direct link interconnects. Figure 2–5 shows a high-level block diagram of the Stratix II ALM while Figure 2–6 shows a detailed view of all the connections in the ALM.

Figure 2-5. High-Level Block Diagram of the Stratix II ALM



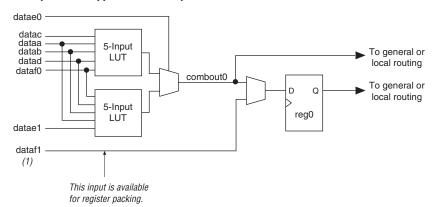


Figure 2–10. Template for Supported Seven-Input Functions in Extended LUT Mode

Note to Figure 2-10:

 If the seven-input function is unregistered, the unused eighth input is available for register packing. The second register, reg1, is not available.

#### Arithmetic Mode

The arithmetic mode is ideal for implementing adders, counters, accumulators, wide parity functions, and comparators. An ALM in arithmetic mode uses two sets of two four-input LUTs along with two dedicated full adders. The dedicated adders allow the LUTs to be available to perform pre-adder logic; therefore, each adder can add the output of two four-input functions. The four LUTs share the dataa and datab inputs. As shown in Figure 2–11, the carry-in signal feeds to adder0, and the carry-out from adder0 feeds to carry-in of adder1. The carry-out from adder1 drives to adder0 of the next ALM in the LAB. ALMs in arithmetic mode can drive out registered and/or unregistered versions of the adder outputs.

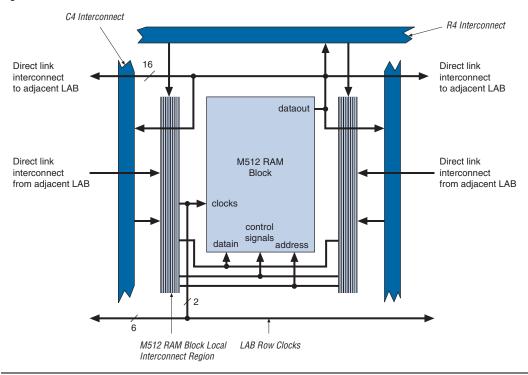


Figure 2-20. M512 RAM Block LAB Row Interface

#### M4K RAM Blocks

The M4K RAM block includes support for true dual-port RAM. The M4K RAM block is used to implement buffers for a wide variety of applications such as storing processor code, implementing lookup schemes, and implementing larger memory applications. Each block contains 4,608 RAM bits (including parity bits). M4K RAM blocks can be configured in the following modes:

- True dual-port RAM
- Simple dual-port RAM
- Single-port RAM
- FIFO
- ROM
- Shift register

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.



When using the global or regional clock control blocks in Stratix II devices to select between multiple clocks or to enable and disable clock networks, be aware of possible narrow pulses or glitches when switching from one clock signal to another. A glitch or runt pulse has a width that is less than the width of the highest frequency input clock signal. To prevent logic errors within the FPGA, Altera recommends that you build circuits that filter out glitches and runt pulses.

Figures 2–37 through 2–39 show the clock control block for the global clock, regional clock, and PLL external clock output, respectively.

Pins PLL Counter Outputs CLKn Internal Pin Logic Static Clock Select (2) This multiplexer supports User-Controllable Dynamic Switching Enable/ Disable Internal Logic **GCLK** 

Figure 2-37. Global Clock Control Blocks

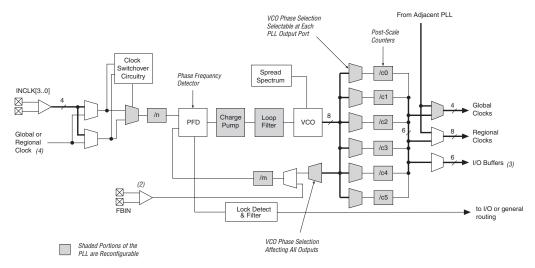
Notes to Figure 2-37:

- These clock select signals can be dynamically controlled through internal logic when the device is operating in user mode.
- (2) These clock select signals can only be set through a configuration file (.sof or .pof) and cannot be dynamically controlled during user mode operation.

#### **Enhanced PLLs**

Stratix II devices contain up to four enhanced PLLs with advanced clock management features. Figure 2–44 shows a diagram of the enhanced PLL.

Figure 2–44. Stratix II Enhanced PLL Note (1)



#### *Notes to Figure 2–44:*

- (1) Each clock source can come from any of the four clock pins that are physically located on the same side of the device as the PLL.
- (2) If the feedback input is used, you lose one (or two, if FBIN is differential) external clock output pin.
- (3) Each enhanced PLL has three differential external clock outputs or six single-ended external clock outputs.
- (4) The global or regional clock input can be driven by an output from another PLL, a pin-driven dedicated global or regional clock, or through a clock control block, provided the clock control block is fed by an output from another PLL or a pin-driven dedicated global or regional clock. An internally generated global signal cannot drive the PLL.

Table 2-	Table 2–14. DQS & DQ Bus Mode Support (Part 2 of 2) Note (1)								
Device	Package	Number of ×4 Groups	Number of ×8/×9 Groups	Number of ×16/×18 Groups	Number of ×32/×36 Groups				
EP2S90	484-pin Hybrid FineLine BGA	8	4	0	0				
	780-pin FineLine BGA	18	8	4	0				
	1,020-pin FineLine BGA	36	18	8	4				
	1,508-pin FineLine BGA	36	18	8	4				
EP2S130	780-pin FineLine BGA	18	8	4	0				
	1,020-pin FineLine BGA	36	18	8	4				
	1,508-pin FineLine BGA	36	18	8	4				
EP2S180	1,020-pin FineLine BGA	36	18	8	4				
	1,508-pin FineLine BGA	36	18	8	4				

Notes to Table 2-14:

A compensated delay element on each DQS pin automatically aligns input DQS synchronization signals with the data window of their corresponding DQ data signals. The DQS signals drive a local DQS bus in the top and bottom I/O banks. This DQS bus is an additional resource to the I/O clocks and is used to clock DQ input registers with the DQS signal.

The Stratix II device has two phase-shifting reference circuits, one on the top and one on the bottom of the device. The circuit on the top controls the compensated delay elements for all DQS pins on the top. The circuit on the bottom controls the compensated delay elements for all DQS pins on the bottom.

Each phase-shifting reference circuit is driven by a system reference clock, which must have the same frequency as the DQS signal. Clock pins CLK[15..12]p feed the phase circuitry on the top of the device and clock pins CLK[7..4]p feed the phase circuitry on the bottom of the device. In addition, PLL clock outputs can also feed the phase-shifting reference circuits.

Figure 2–56 illustrates the phase-shift reference circuit control of each DQS delay shift on the top of the device. This same circuit is duplicated on the bottom of the device.

<sup>(1)</sup> Check the pin table for each DQS/DQ group in the different modes.

Table 2–19. Board Design Recommendations for nCEO								
nCF Innut Buffer Bower in I/O	S	tratix II nCEO V	<sub>ccio</sub> Voltage Le	vel in I/O Bank 7	7			
nCE Input Buffer Power in I/O Bank 3	V <sub>CC10</sub> = 3.3 V	V <sub>CC10</sub> = 2.5 V	V <sub>CC10</sub> = 1.8 V	V <sub>CC10</sub> = 1.5 V	V <sub>CC10</sub> = 1.2 V			
VCCSEL high (V <sub>CCIO</sub> Bank 3 = 1.5 V)	<b>√</b> (1), (2)	<b>✓</b> (3), (4)	<b>√</b> (5)	<b>✓</b>	<b>✓</b>			
VCCSEL high (V <sub>CCIO</sub> Bank 3 = 1.8 V)	<b>√</b> (1), (2)	<b>✓</b> (3), (4)	<b>✓</b>	<b>✓</b>	Level shifter required			
VCCSEL low (nCE Powered by V <sub>CCPD</sub> = 3.3V)	<b>√</b>	<b>√</b> (4)	<b>√</b> (6)	Level shifter required	Level shifter required			

#### Notes to Table 2-19:

- (1) Input buffer is 3.3-V tolerant.
- (2) The nCEO output buffer meets  $V_{OH}$  (MIN) = 2.4 V.
- (3) Input buffer is 2.5-V tolerant.
- (4) The nCEO output buffer meets  $V_{OH}$  (MIN) = 2.0 V.
- (5) Input buffer is 1.8-V tolerant.
- (6) An external 250-Ω pull-up resistor is not required, but recommended if signal levels on the board are not optimal.

For JTAG chains, the TDO pin of the first device drives the TDI pin of the second device in the chain. The  $V_{CCSEL}$  input on JTAG input I/O cells (TCK, TMS, TDI, and TRST) is internally hardwired to GND selecting the 3.3-V/2.5-V input buffer powered by  $V_{CCPD}$ . The ideal case is to have the  $V_{CCIO}$  of the TDO bank from the first device to match the  $V_{CCSEL}$  settings for TDI on the second device, but that may not be possible depending on the application. Table 2–20 contains board design recommendations to ensure proper JTAG chain operation.

Table 2–20. Supported TDO/TDI Voltage Combinations (Part 1 of 2)							
Dovino	TDI Input Buffer Power	Stratix II TDO V <sub>CC10</sub> Voltage Level in I/O Bank 4					
Device		V <sub>CC10</sub> = 3.3 V	V <sub>CC10</sub> = 2.5 V	V <sub>CC10</sub> = 1.8 V	V <sub>CC10</sub> = 1.5 V	V <sub>CC10</sub> = 1.2 V	
Stratix II	Always V <sub>CCPD</sub> (3.3V)	<b>√</b> (1)	<b>√</b> (2)	<b>√</b> (3)	Level shifter required	Level shifter required	

# Document Revision History

Table 2–27 shows the revision history for this chapter.

Date and Document Version	Changes Made	Summary of Changes
May 2007, v4.3	Updated "Clock Control Block" section.	_
	Updated note in the "Clock Control Block" section.	_
	Deleted Tables 2-11 and 2-12.	_
	Updated notes to:  Figure 2–41 Figure 2–42 Figure 2–43 Figure 2–45	<del>-</del>
	Updated notes to Table 2–18.	_
	Moved Document Revision History to end of the chapter.	_
August 2006, v4.2	Updated Table 2–18 with note.	_
April 2006, v4.1	<ul> <li>Updated Table 2–13.</li> <li>Removed Note 2 from Table 2–16.</li> <li>Updated "On-Chip Termination" section and Table 2–19 to include parallel termination with calibration information.</li> <li>Added new "On-Chip Parallel Termination with Calibration" section.</li> <li>Updated Figure 2–44.</li> </ul>	<ul> <li>Added parallel on- chip termination description and specification.</li> <li>Changed RCLK names to match the Quartus II software in Table 2–13.</li> </ul>
December 2005, v4.0	Updated "Clock Control Block" section.	_
July 2005, v3.1	<ul> <li>Updated HyperTransport technology information in Table 2–18.</li> <li>Updated HyperTransport technology information in Figure 2–57.</li> <li>Added information on the asynchronous clear signal.</li> </ul>	_
May 2005, v3.0	<ul> <li>Updated "Functional Description" section.</li> <li>Updated Table 2–3.</li> <li>Updated "Clock Control Block" section.</li> <li>Updated Tables 2–17 through 2–19.</li> <li>Updated Tables 2–20 through 2–22.</li> <li>Updated Figure 2–57.</li> </ul>	_
March 2005, 2.1	<ul><li>Updated "Functional Description" section.</li><li>Updated Table 2–3.</li></ul>	_

Table 5–14. 3.3-V PCI Specifications (Part 2 of 2)								
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit		
$V_{IL}$	Low-level input voltage		-0.3		$0.3 \times V_{CCIO}$	V		
V <sub>OH</sub>	High-level output voltage	$I_{OUT} = -500 \mu A$	$0.9 \times V_{CCIO}$			٧		
V <sub>OL</sub>	Low-level output voltage	$I_{OUT} = 1,500 \mu A$			0.1 × V <sub>CCIO</sub>	V		

Table 5–1	Table 5–15. PCI-X Mode 1 Specifications									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V <sub>CCIO</sub>	Output supply voltage		3.0		3.6	٧				
V <sub>IH</sub>	High-level input voltage		$0.5 \times V_{CCIO}$		V <sub>CCIO</sub> + 0.5	V				
$V_{IL}$	Low-level input voltage		-0.30		$0.35 \times V_{\text{CCIO}}$	V				
$V_{IPU}$	Input pull-up voltage		$0.7 \times V_{CCIO}$			V				
V <sub>OH</sub>	High-level output voltage	$I_{OUT} = -500 \mu A$	$0.9 \times V_{CCIO}$			٧				
V <sub>OL</sub>	Low-level output voltage	$I_{OUT} = 1,500 \mu A$			$0.1 \times V_{CCIO}$	٧				

Table 5-1	6. SSTL-18 Class I Specificat	ions				
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage		1.71	1.80	1.89	٧
$V_{REF}$	Reference voltage		0.855	0.900	0.945	V
V <sub>TT</sub>	Termination voltage		V <sub>REF</sub> - 0.04	$V_{REF}$	V <sub>REF</sub> + 0.04	٧
V <sub>IH</sub> (DC)	High-level DC input voltage		V <sub>REF</sub> + 0.125			V
V <sub>IL</sub> (DC)	Low-level DC input voltage				V <sub>REF</sub> - 0.125	V
V <sub>IH</sub> (AC)	High-level AC input voltage		V <sub>REF</sub> + 0.25			٧
V <sub>IL</sub> (AC)	Low-level AC input voltage				V <sub>REF</sub> - 0.25	V
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -6.7 \text{ mA } (1)$	V <sub>TT</sub> + 0.475			٧
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 6.7 mA (1)			V <sub>TT</sub> – 0.475	V

#### Note to Table 5–16:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 5–33. Stratix II Device Timing Model Status						
Device	Preliminary	Final				
EP2S15		✓				
EP2S30		✓				
EP2S60		✓				
EP2S90		✓				
EP2S130		✓				
EP2S180		✓				

### I/O Timing Measurement Methodology

Altera characterizes timing delays at the worst-case process, minimum voltage, and maximum temperature for input register setup time ( $t_{SU}$ ) and hold time ( $t_{H}$ ). The Quartus II software uses the following equations to calculate  $t_{SU}$  and  $t_{H}$  timing for Stratix II devices input signals.

- $t_{SU}$  = + data delay from input pin to input register
  - + micro setup time of the input register
  - clock delay from input pin to input register
- $t_H = -$  data delay from input pin to input register
  - + micro hold time of the input register
  - + clock delay from input pin to input register

Figure 5–3 shows the setup and hold timing diagram for input registers.

Table 5-	36. Stratix II Performan	ce Notes	(Part 3 of 6)	) Note	e (1)				
		Re	esources Us	ed		Pei	formance	!	
Applications		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
DSP	9 × 9-bit multiplier (5)	0	0	1	430.29	409.16	373.13	320.10	MHz
block	18 × 18-bit multiplier (5)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18 × 18-bit multiplier (7)	0	0	1	450.04	428.08	391.23	335.12	MHz
	36 × 36-bit multiplier (5)	0	0	1	250.00	238.15	217.48	186.60	MHz
	$36 \times 36$ -bit multiplier (6)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18-bit, four-tap FIR filter	0	0	1	410.17	390.01	356.12	305.06	MHz
Larger designs	8-bit,16-tap parallel FIR filter	58	0	4	259.06	240.61	217.15	185.01	MHz
	8-bit, 1024-point, streaming, three multipliers and five adders FFT function	2976	22	9	398.72	364.03	355.23	306.37	MHz
	8-bit, 1024-point, streaming, four multipliers and two adders FFT function	2781	22	12	398.56	409.16	347.22	311.13	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, three multipliers and five adders FFT function	984	5	3	425.17	365.76	346.98	292.39	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, four multipliers and two adders FFT function	919	5	4	427.53	378.78	357.14	307.59	MHz

		Re	esources Us	ed		Pei	formance		
Applications		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, single output, two parallel FFT engines, burst, three multiplier and five adders FFT function	1725	10	6	430.29	401.92	373.13	319.08	MHz
	8-bit, 1024-point, single output, two parallel FFT engines, burst, four multipliers and two adders FFT function	1594	10	8	422.65	407.33	373.13	329.10	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, three multipliers and five adders FFT function	2361	10	9	315.45	342.81	325.73	284.25	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, four multipliers and two adders FFT function	2165	10	12	373.13	369.54	317.96	256.14	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, three multipliers and five adders FFT function	3996	14	18	378.50	367.10	332.33	288.68	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, four multipliers and two adders FFT function	3604	14	24	391.38	361.14	340.25	280.89	MHz

Table 5-	Table 5–36. Stratix II Performance Notes (Part 6 of 6)   Note (1)											
		Resources Used			Performance							
Applications		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit			
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, three multipliers five adders FFT function	7385	60	36	359.58	352.98	312.01	278.00	MHz			
	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, four multipliers and two adders FFT function	6601	60	48	371.88	355.74	327.86	277.62	MHz			

#### Notes for Table 5-36:

- (1) These design performance numbers were obtained using the Quartus II software version 5.0 SP1.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) This application uses registered inputs and outputs.
- (5) This application uses registered multiplier input and output stages within the DSP block.
- (6) This application uses registered multiplier input, pipeline, and output stages within the DSP block.
- (7) This application uses registered multiplier input with output of the multiplier stage feeding the accumulator or subtractor within the DSP block.
- (8) This application uses the same clock source that is globally routed and connected to ports A and B.
- (9) This application uses locally routed clocks or differently sourced clocks for ports A and B.

# **Internal Timing Parameters**

See Tables 5–37 through 5–42 for internal timing parameters.

Table 5	-37. LE_FF Internal Timing Micr	oparam	eters							
Cumbal		-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		
Symbol	Parameter	Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	Unit
t <sub>SU</sub>	LE register setup time before clock	90		95		104 104		121		ps
t <sub>H</sub>	LE register hold time after clock	149		157		172 172		200		ps
t <sub>CO</sub>	LE register clock-to-output delay	62	94	62	99	59 62	109	62	127	ps
t <sub>CLR</sub>	Minimum clear pulse width	204		214		234 234		273		ps
t <sub>PRE</sub>	Minimum preset pulse width	204		214		234 234		273		ps
t <sub>CLKL</sub>	Minimum clock low time	612		642		703 703		820		ps
t <sub>CLKH</sub>	Minimum clock high time	612		642		703 703		820		ps
t <sub>LUT</sub>		162	378	162	397	162 170	435	162	507	ps
t <sub>ADDER</sub>		354	619	354	650	354 372	712	354	829	ps

#### Notes to Table 5-37:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (3) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (4) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

# EP2S90 Clock Timing Parameters

Tables 5–56 through 5–59 show the maximum clock timing parameters for EP2S90 devices.

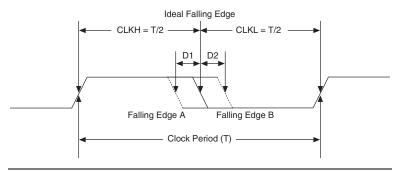
Table 5–56. EP2S90 Column Pins Regional Clock Timing Parameters										
Parameter	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
Parameter	Industrial	Commercial	Grade	Grade	Grade	UIIII				
t <sub>CIN</sub>	1.768	1.850	3.033	3.473	4.040	ns				
t <sub>COUT</sub>	1.611	1.685	2.791	3.195	3.716	ns				
t <sub>PLLCIN</sub>	-0.127	-0.117	0.125	0.129	0.144	ns				
t <sub>PLLCOUT</sub>	-0.284	-0.282	-0.117	-0.149	-0.18	ns				

Table 5–57. EP2S90 Column Pins Global Clock Timing Parameters										
Parameter	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
Parameter	Industrial	Commercial	Grade	Grade	Grade	Ullit				
t <sub>CIN</sub>	1.783	1.868	3.058	3.502	4.070	ns				
t <sub>COUT</sub>	1.626	1.703	2.816	3.224	3.746	ns				
t <sub>PLLCIN</sub>	-0.137	-0.127	0.115	0.119	0.134	ns				
t <sub>PLLCOUT</sub>	-0.294	-0.292	-0.127	-0.159	-0.19	ns				

Table 5–58. EP2S90 Row Pins Regional Clock Timing Parameters										
Parameter	Minimu	m Timing	-3 Speed	-4 Speed	-5 Speed	Unit				
	Industrial	Commercial	Grade	Grade	Grade	Uiiit				
t <sub>CIN</sub>	1.566	1.638	2.731	3.124	3.632	ns				
t <sub>COUT</sub>	1.571	1.643	2.727	3.120	3.627	ns				
t <sub>PLLCIN</sub>	-0.326	-0.326	-0.178	-0.218	-0.264	ns				
t <sub>PLLCOUT</sub>	-0.321	-0.321	-0.182	-0.222	-0.269	ns				

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 7 of 8)											
			Minimu	m Timing	-3	-3	-4	-5 Speed Grade  1943 2033 1928 2018 1917 2007 1923 2013 1916 2006 1680 1770 1691 1781 1700 1790 1942			
I/O Standard	Drive Strength	Parameter	Industrial	Commercial	Speed Grade (3)	Speed Grade (4)	Speed Grade		Unit		
1.8-V	4 mA	t <sub>OP</sub>	912	956	1608	1687	1848	1943	ps		
Differential HSTL Class I		t <sub>DIP</sub>	932	978	1674	1757	1924	2033	ps		
	6 mA	t <sub>OP</sub>	917	962	1595	1673	1833	1928	ps		
		t <sub>DIP</sub>	937	984	1661	1743	1909	2018	ps		
	8 mA	t <sub>OP</sub>	896	940	1586	1664	1823	1917	ps		
		t <sub>DIP</sub>	916	962	1652	1734	1899	2007	ps		
	10 mA	t <sub>OP</sub>	900	944	1591	1669	1828	1923	ps		
		t <sub>DIP</sub>	920	966	1657	1739	1904	2013	ps		
	12 mA	t <sub>OP</sub>	892	936	1585	1663	1821	1916	ps		
		t <sub>DIP</sub>	912	958	1651	1733	1897	2006	ps		
1.8-V	16 mA	t <sub>OP</sub>	877	919	1385	1453	1591	1680	ps		
Differential HSTL Class II		t <sub>DIP</sub>	897	941	1451	1523	1667	1770	ps		
	18 mA	t <sub>OP</sub>	879	921	1394	1462	1602	1691	ps		
		t <sub>DIP</sub>	899	943	1460	1532	1678	1781	ps		
	20 mA	t <sub>OP</sub>	879	921	1402	1471	1611	1700	ps		
		t <sub>DIP</sub>	899	943	1468	1541	1687	1790	ps		
1.5-V	4 mA	t <sub>OP</sub>	912	956	1607	1686	1847	1942	ps		
Differential HSTL Class I		t <sub>DIP</sub>	932	978	1673	1756	1923	2032	ps		
	6 mA	t <sub>OP</sub>	917	961	1588	1666	1825	1920	ps		
		t <sub>DIP</sub>	937	983	1654	1736	1901	2010	ps		
	8 mA	t <sub>OP</sub>	899	943	1590	1668	1827	1922	ps		
		t <sub>DIP</sub>	919	965	1656	1738	1903	2012	ps		
	10 mA	t <sub>OP</sub>	900	943	1592	1670	1829	1924	ps		
		t <sub>DIP</sub>	920	965	1658	1740	1905	2014	ps		
	12 mA	t <sub>OP</sub>	893	937	1590	1668	1827	1922			
		t <sub>DIP</sub>	913	959	1656	1738	1903	2012			

Figure 5-7. Duty Cycle Distortion



DCD expressed in absolution derivation, for example, D1 or D2 in Figure 5–7, is clock-period independent. DCD can also be expressed as a percentage, and the percentage number is clock-period dependent. DCD as a percentage is defined as

(T/2 - D1) / T (the low percentage boundary)

(T/2 + D2) / T (the high percentage boundary)

# **DCD Measurement Techniques**

DCD is measured at an FPGA output pin driven by registers inside the corresponding I/O element (IOE) block. When the output is a single data rate signal (non-DDIO), only one edge of the register input clock (positive or negative) triggers output transitions (Figure 5–8). Therefore, any DCD present on the input clock signal or caused by the clock input buffer or different input I/O standard does not transfer to the output signal.

Figure 5–8. DCD Measurement Technique for Non-DDIO (Single-Data Rate) Outputs

